

Considered as part of IDS filed 3/2/06  
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INFORMATION DISCLOSURE CITATION IN AN APPLICATION						
(PTO-1449)						
ATTY. DOCKET NO. <b>60188-676</b>				SERIAL NO.		
APPLICANT <b>Ryoko MIYACHI, et al.</b>						
FILING DATE <b>October 20, 2003</b>				GROUP		
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		US     2002/0058037-A1	05/09/2002	Weinich et al.		
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FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number + Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation
						Yes      No
		JP 7-86838	09/20/1995			
		JP 2000-155873 A	08/08/2000	NEC IC MICROCOMPUT SYST LTD	JAPAN (w/English Abstract)	
		JP 2000-3268 A	01/07/2000	MITSUBISHI ELECTRIC CORP.	JAPAN (w/English Abstract)	
		JP 5-334055 A	12/17/1993	NEC IC MICROCOMPUT SYST LTD	JAPAN (w/English Abstract)	
		JP 63127340 A	05/31/1988	HITACHI LTD.	ENGLISH ABSTRACT ONLY	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
EXAMINER			DATE CONSIDERED			

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INFORMATION DISCLOSURE  
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APPLICATION

(PTO-1449)

ATTY. DOCKET NO.  
**060188-0676**SERIAL NO.  
**10/687,644**APPLICANT  
**Ryoko MIYACHI, et al.**FILING DATE  
**October 20, 2003**GROUP  
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## U.S. PATENT DOCUMENTS

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## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
DK		JP 2001-154913 A	06/08/2001	HITACHI LTD.		JAPAN (w/English Abstract)

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

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SERIAL NO.

 APPLICANT  
Ryoko MIYACHI, et al.

 FILING DATE  
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GROUP

(PTO-1449)

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EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
DK		US 2002/0058037 A1	05/09/2002	Wolrich et al.	
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DK		JP 2000-155673 A	06/06/2000	NEC IC MICROCOMPUT SYST LTD		JAPAN (w/English Abstract)	
DK		JP 2000-3268 A	01/07/2000	MITSUBISHI ELECTRIC CORP.		JAPAN (w/English Abstract)	
DK		JP 5-334055 A	12/17/1993	NEC IC MICROCOMPUT SYST LTD		JAPAN (w/English Abstract)	
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